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Author Index

Adhi, K.P., R.L. Owings, T.A. Railkar, W.D. Brown and A.P. Malshe, Femtosecond		Dulcey, C.S., see Chaney, J.A.	218 (2003) 258
ultraviolet (248 nm) excimer laser proces-		Farías, M.H., see Soto, G.	218 (2003) 281
sing of Teflon (PTFE)	218 (2003) 17	Farkas, A.P., see Óvári, L.	218 (2003) 329
Akmil Başar, C., A. Karagunduz, B. Keskinler		Farquhar, M.L., P.L. Wincott, R.A. Wogelius	
and A. Cakici, Effect of presence of ions on		and D.J. Vaughan, Electrochemical oxida-	
surface characteristics of surfactant modi-		tion of the chalcopyrite surface: an XPS and	
fied powdered activated carbon (PAC)	218 (2003) 169	AFM study in solution at pH 4	218 (2003) 34
Allen, L.P., see Li, X.	218 (2003) 250		
Amalnerkar, D.P., see Pathan, H.M.	218 (2003) 290	Gesheva, K., see Tanner, R.E.	218 (2003) 162
		Gogova, D., see Tanner, R.E.	218 (2003) 162
Bae, C.H., see Park, S.M.	218 (2003) 310	Goodhue, W.D., see Li, X.	218 (2003) 250
Bai, X.D., see Peng, D.Q.	218 (2003) 7	Göthelid, M., see Weissenrieder, J.	218 (2003) 154
Belkacem, Y., see Keffous, A.	218 (2003) 336	Guo, Y., DH. Qin, JB. Ding and HL. Li,	
Bhattacharya, M., W.G. Devi and P.S. Mazum-		Annealing and morphology effects on the	
dar, Determination of kinetic parameters		Fe _{0.39} Co _{0.61} nanowire arrays	218 (2003) 106
from temperature programmed desorption			, , ,
curves	218 (2003) 1	Ha, J.S., see Park, S.M.	218 (2003) 310
Bliss, D., see Li, X.	218 (2003) 250	Hong, L., see Jiang, H.	218 (2003) 305
Brown, W.D., see Adhi, K.P.	218 (2003) 17	Hou, YQ., DM. Zhuang, G. Zhang, M. Zhao	
		and MS. Wu, Influence of annealing tem-	
Cakici, A., see Akmil Başar, C.	218 (2003) 169	perature on the properties of titanium oxide	
Castillón, F.F., see Soto, G.	218 (2003) 281	thin film	218 (2003) 97
Chaikittisilp, S., see Lothongkum, G.	218 (2003) 202		
Chaney, J.A., S.E. Koh, C.S. Dulcey and P.E.		Iroh, J.O., see Rajagopalan, R.	218 (2003) 58
Pehrsson, Surface chemistry of carbon			
removal from indium tin oxide by base		Jang, Y.R., see Park, S.M.	218 (2003) 310
and plasma treatment, with implications		Ji, V., see Zhang, Jm.	218 (2003) 267
on hydroxyl termination	218 (2003) 258	Jiang, H., X. Chen and L. Hong, Mineral-acid-	
Chazalviel, JN., see Sigaud, P.	218 (2003) 54	free chemical polishing solutions for fer-	
Chen, S.H., see Ma, H.Y.	218 (2003) 143	rous alloys	218 (2003) 305
Chen, W., X. Li, G. Xue, Z. Wang and W. Zou,		Jin, F., see Xu, XH.	218 (2003) 29
Magnetic and conducting particles: pre-		Jin, P., S.H. Pan, Y.G. Li, C.Z. Zhang and Z.G.	
paration of polypyrrole layer on Fe ₃ O ₄		Wang, Electronic properties of sulfur pas-	
nanospheres	218 (2003) 215	sivated undoped-n+ type GaAs surface stu-	
Chen, X., see Jiang, H.	218 (2003) 305	died by photoreflectance	218 (2003) 210
Chen, X.W., see Peng, D.Q.	218 (2003) 7		
Chen, Z., see Wang, W.	218 (2003) 24	Kabasakaloğlu, M., M. Talu, F. Yıldırım and	
Cheng, X., see Lian, J.	218 (2003) 12	B. Sarı, The electrochemical homopoly-	
Chergui, W., see Keffous, A.	218 (2003) 336	merization of furan and thiophene and the	
		structural elucidation of their bipolymer	
Dahmani, A., see Keffous, A.	218 (2003) 336	films	218 (2003) 84
Díaz, J.A., see Soto, G.	218 (2003) 281	Kang, E.T., see Wang, J.G.	218 (2003) 231
De La Cruz, W., see Soto, G.	218 (2003) 281	Karagunduz, A., see Akmil Başar, C.	218 (2003) 169
Deshmukh, N., see Mukherjee, M.	218 (2003) 323	Karlsson, U.O., see Weissenrieder, J.	218 (2003) 154
Devi, W.G., see Bhattacharya, M.	218 (2003) 1	Kawakami, Y., and E. Ozawa, Tungsten micro-	
Ding, JB., see Guo, Y.	218 (2003) 106	cone growth by laser irradiation	218 (2003) 175
Duan, JF., see Xu, XH.	218 (2003) 29	Kefalas, D., see Leftheriotis, G.	218 (2003) 275

Keffous, A., M. Siad, S. Mamma, Y. Belkacem,		Lu, M., M.K. Li, Z.J. Zhang and H.L. Li,	
C. Lakhdar Chaouch, H. Menari, A. Dah-		Synthesis of carbon nanotubes/Si nano-	
mani and W. Chergui, Effect of series resis-		wires core-sheath structure arrays and their	219 (2002) 105
tance on the performance of high resistivity	219 (2002) 226	field emission properties Lu, Q., see Liu, X.	218 (2003) 195 218 (2003) 137
silicon Schottky diode	218 (2003) 336		218 (2003) 137
Keskinler, B., see Akmil Başar, C.	218 (2003) 169	Luo, J.L., see Ma, H.Y.	218 (2003) 143
Kim, D., Deposition of indium tin oxide films on polycarbonate substrates by direct metal		W WW GW DOW GWI'GH G	
ion beam deposition	218 (2003) 70	Ma, H.Y., C. Yang, B.S. Yin, G.Y. Li, S.H. Chen	
AFM study of the effect of direct negative Ni ion	218 (2003) 70	and J.L. Luo, Electrochemical characteriza-	
beam energy on the evolution of Ni nano-		tion of copper surface modified by <i>n</i> -alka-	219 (2002) 142
islands	218 (2003) 78	nethiols in chloride-containing solutions	218 (2003) 143 218 (2003) 250
Kiss, J., see Óvári, L.	218 (2003) 329	MacCrimmon, R., see Li, X. Machorro, R., see Soto, G.	218 (2003) 281
Koh, S.E., see Chaney, J.A.	218 (2003) 258	Malshe, A.P., see Adhi, K.P.	218 (2003) 17
Krishnaswami, K., see Li, X.	218 (2003) 250	Mamma, S., see Keffous, A.	218 (2003) 336
Kulka, M., and A. Pertek, Characterization of	(Mazumdar, P.S., see Bhattacharya, M.	218 (2003) 1
complex $(B + C + N)$ diffusion layers		Menari, H., see Keffous, A.	218 (2003) 336
formed on chromium and nickel-based		Mukherjee, M., N. Deshmukh and S.K. Kulk-	210 (2003) 330
low-carbon steel	218 (2003) 113	arni, X-ray reflectivity and AFM studies of	
Kulkarni, S.K., see Mukherjee, M.	218 (2003) 323	polystyrene-CdS nanocomposite thin films	218 (2003) 323
Kuo, Y., see Ristova, M.	218 (2003) 44	polystyrene cub nanocomposite timi mins	210 (2003) 525
		Nam, S.H., see Park, S.M.	218 (2003) 310
Lahlil, K., see Sigaud, P.	218 (2003) 54	Neoh, K.G., see Wang, J.G.	218 (2003) 310
Lakhdar Chaouch, C., see Keffous, A.	218 (2003) 336	Neon, R.G., see Wang, J.G.	216 (2003) 231
Lee, H.H., see Ristova, M.	218 (2003) 44	ACT THE ADDITION OF COLUMN	
Lee, ZY., see Xu, XH.	218 (2003) 29	Óvári, L., J. Kiss, A.P. Farkas and F. Solymosi,	
Leftheriotis, G., S. Papaefthimiou, P. Yianoulis,		Adsorption geometry of ethyl iodide on	
A. Siokou and D. Kefalas, Structural and		clean and oxygen covered Ru(001) sur-	219 (2002) 220
electrochemical properties of opaque sol-		faces: LEIS, XPS and TDS study	218 (2003) 329
gel deposited WO ₃ layers	218 (2003) 275	Owings, R.L., see Adhi, K.P. Ozanam, F., see Sigaud, P.	218 (2003) 17 218 (2003) 54
Leygraf, C., see Weissenrieder, J.	218 (2003) 154	Ozawa, E., see Kawakami, Y.	218 (2003) 34
Li, F., see Liu, X.	218 (2003) 137	Ozawa, E., see Kawakaiii, 1.	216 (2003) 173
Li, G.Y., see Ma, H.Y.	218 (2003) 143	B GH F B	210 (2002) 210
Li, HL., see Guo, Y.	218 (2003) 106	Pan, S.H., see Jin, P.	218 (2003) 210
Li, H.L., see Lu, M.	218 (2003) 195	Pan, W.J., J. Sun, H. Ling, N. Xu, Z.F. Ying and	
Li, M.K., see Lu, M.	218 (2003) 195	J.D. Wu, Preparation of thin films of	219 (2002) 207
Li, X., see Chen, W.	218 (2003) 215	carbon-based compounds	218 (2003) 297
Li, X., W.D. Goodhue, C. Santeufeimio, T.G.		Papaefthimiou, S., see Leftheriotis, G.	218 (2003) 275
Tetreault, R. MacCrimmon, L.P. Allen, D.		Park, S.M., C.H. Bae, S.H. Nam, Y.R. Jang,	
Bliss, K. Krishnaswami and C. Sung, Gas		K.H. Yoo and J.S. Ha, The effects of ambi-	
cluster ion beam processing of gallium		ent He pressure on the oxygen density of Er-doped SiO_x thin films grown by laser	
antimonide wafers for surface and sub-	210 (2002) 250	ablation of a Si: Er_2O_3 target	218 (2003) 310
surface damage reduction	218 (2003) 250	Pathan, H.M., C.D. Lokhande, D.P. Amalnerkar	218 (2003) 310
Li, Y.G., see Jin, P.	218 (2003) 210	and T. Seth, Preparation and characteriza-	
Lian, J., Q. Wang, X. Cheng, A. Wei and Y.	219 (2002) 12	tion of copper telluride thin films by mod-	
Wang, Study on the surface of AlGaInP	218 (2003) 12	ified chemical bath deposition (M-CBD)	
Ling, H., see Pan, W.J.	218 (2003) 297	method	218 (2003) 290
Liu, X., F. Li, Q. Lu, Y. Xia and C. Zhang, Study		Pehrsson, P.E., see Chaney, J.A.	218 (2003) 258
of range distribution parameters for fluor-	218 (2003) 137	Peng, D.Q., X.D. Bai, X.W. Chen, Q.G. Zhou,	210 (2003) 230
ine ions implantation in AgGaS ₂ crystal	218 (2003) 137	X.Y. Liu and R.H. Yu, Effect of cerium ion	
Liu, X.Y., see Peng, D.Q. Lokhande, C.D., see Pathan, H.M.	218 (2003) 290	implantation on the aqueous corrosion	
Long, Z.L., Y.C. Zhou and L. Xiao, Character-	218 (2003) 290	behavior of zircaloy-4	218 (2003) 7
ization of black chromate conversion coat-		Pertek, A., see Kulka, M.	218 (2003) 113
ing on the electrodeposited zinc-iron alloy	218 (2003) 123	Popa, M.E., see Rusu, G.I.	218 (2003) 222
Lothongkum, A.W., see Lothongkum, G.	218 (2003) 202	*	, , , , , , , , , , , , , , , , , , ,
Lothongkum, G., S. Chaikittisilp and A.W.	210 (2003) 202	Qin, DH., see Guo, Y.	218 (2003) 106
Lothongkum, XPS investigation of surface		Qu, L., see Wang, W.	218 (2003) 100
films on high Cr-Ni ferritic and austenitic		Cu, 20, 500 mang, m.	210 (2003) 24
stainless steels	218 (2003) 202	Railkar, T.A., see Adhi, K.P.	218 (2003) 17
			210 (2005) 17

Rajagopalan, R., and J.O. Iroh, Characteriza-		Wang, W., L. Qu, G. Yang and Z. Chen, Large	
tion of polyaniline-polypyrrole composite		third-order optical nonlinearity in BaTiO ₃	
coatings on low carbon steel: a XPS and		matrix-embedded metal nanoparticles	218 (2003) 24
infrared spectroscopy study	218 (2003) 58	Wang, Y., see Lian, J.	218 (2003) 12
Ramsier, R.D., see Stojilovic, N.	218 (2003) 188	Wang, Z., see Chen, W.	218 (2003) 215
Ristova, M., Y. Kuo and H.H. Lee, Study of		Wang, Z.G., see Jin, P.	218 (2003) 210
hydrogenated amorphous silicon thin films		Weber, D.W., see Stojilovic, N.	218 (2003) 188
as a potential sensor for He–Ne laser light		Wei, A., see Lian, J.	218 (2003) 12
detection	218 (2003) 44	Weissenrieder, J., C. Leygraf, M. Göthelid and	210 (2000) 12
Rusu, G.G., see Rusu, G.I.	218 (2003) 222	U.O. Karlsson, Photoelectron microscopy	
Rusu, G.I., M.E. Popa, G.G. Rusu and I.	210 (2003) 222	of filiform corrosion of aluminum	218 (2003) 154
Salaoru, On the electronic transport proper-		Wincott, P.L., see Farquhar, M.L.	218 (2003) 134
		• • • • • • • • • • • • • • • • • • •	
ties of polycrystalline ZnSe films	218 (2003) 222	Wogelius, R.A., see Farquhar, M.L.	218 (2003) 34
		Wu, HS., see Xu, XH.	218 (2003) 29
Salaoru, I., see Rusu, G.I.	218 (2003) 222	Wu, J.D., see Pan, W.J.	218 (2003) 297
Santeufeimio, C., see Li, X.	218 (2003) 250	Wu, MS., see Hou, YQ.	218 (2003) 97
Sarı, B., see Kabasakaloğlu, M.	218 (2003) 84	Via V see Lin V	219 (2002) 127
Seth, T., see Pathan, H.M.	218 (2003) 290	Xia, Y., see Liu, X.	218 (2003) 137
Siad, M., see Keffous, A.	218 (2003) 336	Xiao, L., see Long, Z.L.	218 (2003) 123
Sigaud, P., JN. Chazalviel, F. Ozanam and K.	210 (2000) 000	Xu, KW., see Zhang, JM.	218 (2003) 245
Lahlil, Increased hole injection in organic		Xu, Kw., see Zhang, Jm.	218 (2003) 267
diodes by grafting of dipolar molecules on		Xu, N., see Pan, W.J.	218 (2003) 297
indium-tin oxide	219 (2002) 54	Xu, XH., HS. Wu, JF. Duan, F. Wang, F. Jin	
	218 (2003) 54	and ZY. Lee, Statistical approach for the	
Siokou, A., see Leftheriotis, G.	218 (2003) 275	optimal deposition of Cr underlayer for	
Solymosi, F., see Ovári, L.	218 (2003) 329	SmCo/Cr magnetic films	218 (2003) 29
Soto, G., W. De La Cruz, J.A. Díaz, R.		Xue, G., see Chen, W.	218 (2003) 215
Machorro, F.F. Castillón and M.H. Farías,		V C W- H.V.	219 (2002) 142
Characterization of tungsten oxide films		Yang, C., see Ma, H.Y.	218 (2003) 143
produced by reactive pulsed laser deposi-	210 (2002) 201	Yang, G., see Wang, W.	218 (2003) 24
tion	218 (2003) 281	Yianoulis, P., see Leftheriotis, G.	218 (2003) 275
Stamate, M.D., On the dielectric properties of		Yin, B.S., see Ma, H.Y.	218 (2003) 143
dc magnetron TiO ₂ thin films	218 (2003) 317	Ying, Z.F., see Pan, W.J.	218 (2003) 297
Stojilovic, N., D.W. Weber and R.D. Ramsier,		Yıldırım, F., see Kabasakaloğlu, M.	218 (2003) 84
Interaction of methanol with Zr(0 0 0 1)	218 (2003) 188	Yoo, K.H., see Park, S.M.	218 (2003) 310
Sun, J., see Pan, W.J.	218 (2003) 297	Yu, R.H., see Peng, D.Q.	218 (2003) 7
Sung, C., see Li, X.	218 (2003) 250		
Szekeres, A., see Tanner, R.E.	218 (2003) 162	Zhang, C., see Liu, X.	218 (2003) 137
		Zhang, C.Z., see Jin, P.	218 (2003) 210
Talu, M., see Kabasakaloğlu, M.	218 (2003) 84	Zhang, G., see Hou, YQ.	218 (2003) 97
	210 (2003) 04	Zhang, JM., and KW. Xu, Theoretical	
Tanner, R.E., A. Szekeres, D. Gogova and K.		analysis of strain energy-driven abnormal	
Gesheva, Study of the surface roughness of	210 (2002) 162	grain growth in metallic films with hcp	
CVD-tungsten oxide thin films	218 (2003) 162	((c/a) < 1.633) structure on rigid substrates	218 (2003) 245
Tetreault, T.G., see Li, X.	218 (2003) 250	Zhang, Jm., Kw. Xu and V. Ji, Experiment	
		and simulation of grain growth in a bidi-	
Vaughan, D.J., see Farquhar, M.L.	218 (2003) 34	mensional polycrystalline film	218 (2003) 267
		Zhang, Z.J., see Lu, M.	218 (2003) 195
Wang, F., see Xu, XH.	218 (2003) 29	Zhao, M., see Hou, YQ.	218 (2003) 97
Wang, J.G., K.G. Neoh and E.T. Kang, Polyani-	210 (2003) 29	Zhou, Q.G., see Peng, D.Q.	218 (2003) 7
		Zhou, Y.C., see Long, Z.L.	218 (2003) 123
line-palladium composite coatings for	218 (2002) 221	Zhou, T.C., see Long, Z.L. Zhuang, DM., see Hou, YQ.	218 (2003) 97
metallization of polyethylene substrate	218 (2003) 231	Zou, W., see Chen, W.	218 (2003) 215
Wang, Q., see Lian, J.	218 (2003) 12	20a, W., see Chen, W.	210 (2003) 213



Applied Surface Science 218 (2003) IV-XII



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Subject Index

Ablation		Experiment and simulation of grain growth in a bidimensional polycrystalline film, Jm.	218 (2002) 267
The effects of ambient He pressure on the oxygen density of Er-doped SiO _x thin films grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang,		Zhang, Kw. Xu and V. Ji Antimony	218 (2003) 267
K.H. Yoo and J.S. Ha	218 (2003) 310		
		Gas cluster ion beam processing of gallium antimonide wafers for surface and sub-surface damage reduction, X. Li,	
Alloys		W.D. Goodhue, C. Santeufeimio, T.G. Tetreault, R. MacCrimmon, L.P. Allen, D.	
Effect of cerium ion implantation on the aqueous corrosion behavior of zircaloy-4, D.Q. Peng, X.D. Bai, X.W. Chen, Q.G.		Bliss, K. Krishnaswami and C. Sung	218 (2003) 250
Zhou, X.Y. Liu and R.H. Yu Statistical approach for the optimal deposition	218 (2003) 7	Atomic force microscopy	
of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F. Wang, F. Jin and ZY. Lee	218 (2003) 29	Electrochemical oxidation of the chalcopyrite surface: an XPS and AFM study in solution	
Mineral-acid-free chemical polishing solutions for ferrous alloys, H. Jiang, X. Chen and L.		at pH 4, M.L. Farquhar, P.L. Wincott, R.A. Wogelius and D.J. Vaughan	218 (2003) 34
Hong	218 (2003) 305	Deposition of indium tin oxide films on poly- carbonate substrates by direct metal ion beam deposition, D. Kim	218 (2003) 70
		AFM study of the effect of direct negative Ni	210 (2000)
Aluminium		ion beam energy on the evolution of Ni nanoislands, D. Kim	218 (2003) 78
Study on the surface of AlGaInP, J. Lian, Q.		Annealing and morphology effects on the Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo,	
Wang, X. Cheng, A. Wei and Y. Wang Photoelectron microscopy of filiform corrosion	218 (2003) 12	DH. Qin, JB. Ding and HL. Li Study of the surface roughness of CVD-tung-	00 (2003) 106
of aluminum, J. Weissenrieder, C. Leygraf, M. Göthelid and U.O. Karlsson	218 (2003) 154	sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162
Effect of series resistance on the performance of high resistivity silicon Schottky diode, A. Keffous, M. Siad, S. Mamma, Y. Belkacem,	210 (2005) 151	Synthesis of carbon nanotubes/Si nanowires core-sheath structure arrays and their field emission properties, M. Lu, M.K. Li, Z.J.	218 (2003) 102
C. Lakhdar Chaouch, H. Menari, A. Dah-		Zhang and H.L. Li	218 (2003) 195
mani and W. Chergui	218 (2003) 336	On the electronic transport properties of polycrystalline ZnSe films, G.I. Rusu, M.E.	
		Popa, G.G. Rusu and I. Salaoru Gas cluster ion beam processing of gallium	218 (2003) 222
Annealing		antimonide wafers for surface and sub-sur- face damage reduction, X. Li, W.D. Good-	
Annealing and morphology effects on the		hue, C. Santeufeimio, T.G. Tetreault, R.	
Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, DH. Qin, JB. Ding and HL. Li	00 (2003) 106	MacCrimmon, L.P. Allen, D. Bliss, K. Krishnaswami and C. Sung	218 (2003) 250
Z. II. VIII, J. D. DING UNG II. D. DI	00 (2003) 100	and c. builg	210 (2003) 230

Auger electron spectroscopy		Chromium	
Interaction of methanol with Zr(0 0 0 1), N. Stojilovic, D.W. Weber and R.D. Ramsier Surface chemistry of carbon removal from indium tin oxide by base and plasma treat-	218 (2003) 188	Statistical approach for the optimal deposition of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F. Wang, F. Jin and ZY. Lee	218 (2003) 29
ment, with implications on hydroxyl termi- nation, J.A. Chaney, S.E. Koh, C.S. Dulcey and P.E. Pehrsson Characterization of tungsten oxide films pro-	218 (2003) 258	XPS investigation of surface films on high Cr- Ni ferritic and austenitic stainless steels, G. Lothongkum, S. Chaikittisilp and A.W. Lothongkum	218 (2003) 202
duced by reactive pulsed laser deposition, G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2002) 281	Clusters	210 (2003) 202
R. Machorio, F.F. Castillon and M.H. Farias	218 (2003) 281		
Baron Characterization of complex (B + C + N) diffusion layers formed on chromium and nickel-based low-carbon steel, M. Kulka		Gas cluster ion beam processing of gallium antimonide wafers for surface and sub-surface damage reduction, X. Li, W.D. Goodhue, C. Santeufeimio, T.G. Tetreault, R. MacCrimmon, L.P. Allen, D. Bliss, K. Krishnaswami and C. Sung	218 (2003) 250
and A. Pertek	218 (2003) 113		
		Cobalt	
Carbon		Statistical approach for the optimal deposition of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F.	
Characterization of complex (B + C + N) diffusion layers formed on chromium and nickel-based low-carbon steel, M. Kulka		Wang, F. Jin and ZY. Lee Annealing and morphology effects on the Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, D	218 (2003) 29
and A. Pertek Synthesis of carbon nanotubes/Si nanowires	218 (2003) 113	H. Qin, JB. Ding and HL. Li	106 (2003) 106
core-sheath structure arrays and their field		()	
emission properties, M. Lu, M.K. Li, Z.J. Zhang and H.L. Li	218 (2003) 195	Computer simulations	
Surface chemistry of carbon removal from indium tin oxide by base and plasma treatment, with implications on hydroxyl termination, J.A. Chaney, S.E. Koh, C.S. Dulcey and P.E. Pehrsson	218 (2003) 258	Experiment and simulation of grain growth in a bidimensional polycrystalline film, Jm. Zhang, Kw. Xu and V. Ji	218 (2003) 267
		Copper	
Cerium		Electrochemical oxidation of the chalcopyrite surface: an XPS and AFM study in solution	
Effect of cerium ion implantation on the aqueous corrosion behavior of zircaloy-4, D.Q. Peng, X.D. Bai, X.W. Chen, Q.G. Zhou,	210 (2002)	at pH 4, M.L. Farquhar, P.L. Wincott, R.A. Wogelius and D.J. Vaughan Electrochemical characterization of copper surface modified by <i>n</i> -alkanethiols in	218 (2003) 34
X.Y. Liu and R.H. Yu	218 (2003) 7	chloride-containing solutions, H.Y. Ma, C. Yang, B.S. Yin, G.Y. Li, S.H. Chen and J.L. Luo	218 (2003) 143
Chemical vapour deposition		Experiment and simulation of grain growth in a bidimensional polycrystalline film, Jm.	
Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and		Zhang, Kw. Xu and V. Ji Corrosion	218 (2003) 267
H.H. Lee Study of the surface roughness of CVD-tung-	218 (2003) 44		
sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162	Effect of cerium ion implantation on the aqueous corrosion behavior of zircaloy-4, D.Q.	

Peng, X.D. Bai, X.W. Chen, Q.G. Zhou, X.Y. Liu and R.H. Yu	218 (2003) 7	elucidation of their bipolymer films, M. Kabasakaloğlu, M. Talu, F. Yıldırım and	
Photoelectron microscopy of filiform corrosion of aluminum, J. Weissenrieder, C. Leygraf,	218 (2003)	B. Sarı Annealing and morphology effects on the	218 (2003) 84
M. Göthelid and U.O. Karlsson XPS investigation of surface films on high Cr-	218 (2003) 154	Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, D H. Qin, JB. Ding and HL. Li	106 (2003) 106
Ni ferritic and austenitic stainless steels, G. Lothongkum, S. Chaikittisilp and A.W. Lothongkum	218 (2003) 202	Characterization of complex (B + C + N) diffusion layers formed on chromium and nickel-based low-carbon steel, M. Kulka	100 (2002) 100
		and A. Pertek	218 (2003) 113
Diodes		Photoelectron microscopy of filiform corrosion of aluminum, J. Weissenrieder, C. Leygraf, M. Göthelid and U.O. Karlsson	218 (2003) 154
Increased hole injection in organic diodes by grafting of dipolar molecules on indium-tin		Study of the surface roughness of CVD-tung-	210 (2002) 10 .
oxide, P. Sigaud, JN. Chazalviel, F. Oza-	210 (2002) 54	sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162
nam and K. Lahlil	218 (2003) 54	Tungsten microcone growth by laser irradia- tion, Y. Kawakami and E. Ozawa	218 (2003) 175
Electrical properties		Synthesis of carbon nanotubes/Si nanowires core-sheath structure arrays and their field emission properties, M. Lu, M.K. Li, Z.J.	
The electrochemical homopolymerization of furan and thiophene and the structural		Zhang and H.L. Li	218 (2003) 195
elucidation of their bipolymer films, M.		Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres,	
Kabasakaloğlu, M. Talu, F. Yıldırım and B. Sarı	218 (2003) 84	W. Chen, X. Li, G. Xue, Z. Wang and W. Zou	218 (2003) 215
Electrochemical characterization of copper sur- face modified by <i>n</i> -alkanethiols in chloride-		Polyaniline-palladium composite coatings for metallization of polyethylene substrate,	
containing solutions, H.Y. Ma, C. Yang, B.S. Yin, G.Y. Li, S.H. Chen and J.L. Luo	218 (2003) 143	J.G. Wang, K.G. Neoh and E.T. Kang Experiment and simulation of grain growth in a	218 (2003) 231
On the electronic transport properties of polycrystalline ZnSe films, G.I. Rusu, M.E.		bidimensional polycrystalline film, Jm. Zhang, Kw. Xu and V. Ji	218 (2003) 267
Popa, G.G. Rusu and I. Salaoru Effect of series resistance on the performance	218 (2003) 222	Structural and electrochemical properties	218 (2003) 207
of high resistivity silicon Schottky diode, A. Keffous, M. Siad, S. Mamma, Y. Belkacem,		of opaque sol-gel deposited WO ₃ layers, G. Leftheriotis, S. Papaefthimiou, P. Yia- noulis, A. Siokou and D. Kefalas	218 (2003) 275
C. Lakhdar Chaouch, H. Menari, A. Dahmani and W. Chergui	218 (2003) 336	The effects of ambient He pressure on the oxygen density of Er-doped SiO_x thin films	210 (2003) 273
Electron energy loss spectroscopy		grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang,	219 (2002) 210
		K.H. Yoo and J.S. Ha	218 (2003) 310
Surface chemistry of carbon removal from indium tin oxide by base and plasma treat-			
ment, with implications on hydroxyl termination, J.A. Chaney, S.E. Koh, C.S. Dulcey		Ellipsometry	
and P.E. Pehrsson	218 (2003) 258	Study on the surface of AlGaInP, J. Lian, Q.	
Characterization of tungsten oxide films produced by reactive pulsed laser deposition,		Wang, X. Cheng, A. Wei and Y. Wang Study of the surface roughness of CVD-tung-	218 (2003) 12
G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2003) 281	sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162
Electron microscopy			
		Erbium	
Femtosecond ultraviolet (248 nm) excimer laser processing of Teflon (PTFE), K.P.		The effects of ambient He pressure on the	
Adhi, R.L. Owings, T.A. Railkar, W.D. Brown and A.P. Malshe	218 (2003) 17	oxygen density of Er-doped SiO_x thin films grown by laser ablation of a $Si:Er_2O_3$ target,	
The electrochemical homopolymerization of furan and thiophene and the structural	210 (2000) 11	S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310

Evaporation		Halogens	
On the electronic transport properties of polycrystalline ZnSe films, G.I. Rusu, M.E. Popa, G.G. Rusu and I. Salaoru	218 (2003) 222	Study of range distribution parameters for fluorine ions implantation in AgGaS ₂ crystal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang	218 (2003) 137
Field emission		Adsorption geometry of ethyl iodide on clean and oxygen covered Ru(001) surfaces: LEIS, XPS and TDS study, L. Óvári, J.	210 (2003) 137
Synthesis of carbon nanotubes/Si nanowires core-sheath structure arrays and their field		Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329
emission properties, M. Lu, M.K. Li, Z.J. Zhang and H.L. Li	218 (2003) 195	Helium	
Gallium		The effects of ambient He pressure on the oxygen density of Er-doped SiO_x thin films grown by laser ablation of a $Si:Er_2O_3$ target,	
Study on the surface of AlGaInP, J. Lian, Q. Wang, X. Cheng, A. Wei and Y. Wang Study of range distribution parameters for	218 (2003) 12	S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310
fluorine ions implantation in AgGaS ₂ crystal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang Gas cluster ion beam processing of gallium	218 (2003) 137	Hydrogen	
antimonide wafers for surface and sub-surface damage reduction, X. Li, W.D. Goodhue, C. Santeufeimio, T.G. Tetreault, R. MacCrimmon, L.P. Allen, D. Bliss, K. Krishnaswami and C. Sung	218 (2003) 250	Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and H.H. Lee	218 (2003) 44
		Indium	
Gallium arsenide Electronic properties of sulfur passivated undoped-n ⁺ type GaAs surface studied by		Study on the surface of AlGaInP, J. Lian, Q. Wang, X. Cheng, A. Wei and Y. Wang	218 (2003) 12
photoreflectance, P. Jin, S.H. Pan, Y.G. Li, C.Z. Zhang and Z.G. Wang	218 (2003) 210	Indium tin oxide Increased hole injection in organic diodes by	
Gold		grafting of dipolar molecules on indium-tin oxide, P. Sigaud, JN. Chazalviel, F. Ozanam and K. Lahlil	218 (2003) 54
Effect of series resistance on the performance of high resistivity silicon Schottky diode, A. Keffous, M. Siad, S. Mamma, Y. Belkacem,		Deposition of indium tin oxide films on poly- carbonate substrates by direct metal ion beam deposition, D. Kim	218 (2003) 70
C. Lakhdar Chaouch, H. Menari, A. Dahmani and W. Chergui	218 (2003) 336	Surface chemistry of carbon removal from indium tin oxide by base and plasma treat- ment, with implications on hydroxyl termi- nation, J.A. Chaney, S.E. Koh, C.S. Dulcey	
Hafnium		and P.E. Pehrsson	218 (2003) 258
Theoretical analysis of strain energy-driven abnormal grain growth in metallic films with hcp $((c/a) < 1.633)$ structure on rigid		Infrared spectroscopy	
substrates, JM. Zhang and KW. Xu	218 (2003) 245	Femtosecond ultraviolet (248 nm) excimer laser processing of Teflon (PTFE), K.P. Adhi, R.L. Owings, T.A. Railkar, W.D.	
Halogenides Photoelectron microscopy of filiform corrosion		Brown and A.P. Malshe Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser	218 (2003) 17
of aluminum, J. Weissenrieder, C. Leygraf, M. Göthelid and U.O. Karlsson	218 (2003) 154	light detection, M. Ristova, Y. Kuo and H.H. Lee	218 (2003) 44

Subject Index

Increased hole injection in organic diodes by grafting of dipolar molecules on indium—tin oxide, P. Sigaud, JN. Chazalviel, F. Oza-		LEIS, XPS and TDS study, L. Óvári, J. Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329
nam and K. Lahlil	218 (2003) 54		
Characterization of polyaniline-polypyrrole composite coatings on low carbon steel: a XPS and infrared spectroscopy study, R.		Iron	
Rajagopalan and J.O. Iroh Electrochemical characterization of copper surface modified by <i>n</i> -alkanethiols in chloride-containing solutions, H.Y. Ma, C. Yang, B.S. Yin, G.Y. Li, S.H. Chen and J.L.	218 (2003) 58	Electrochemical oxidation of the chalcopyrite surface: an XPS and AFM study in solution at pH 4, M.L. Farquhar, P.L. Wincott, R.A. Wogelius and D.J. Vaughan Annealing and morphology effects on the	218 (2003) 34
Luo Photoelectron microscopy of filiform corrosion	218 (2003) 143	Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, DH. Qin, JB. Ding and HL. Li	106 (2003) 106
of aluminum, J. Weissenrieder, C. Leygraf, M. Göthelid and U.O. Karlsson Magnetic and conducting particles: preparation	218 (2003) 154	Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres, W. Chen, X. Li, G. Xue, Z. Wang and W.	
of polypyrrole layer on Fe ₃ O ₄ nanospheres, W. Chen, X. Li, G. Xue, Z. Wang and W. Zou	218 (2003) 215	Zou Mineral-acid-free chemical polishing solutions for ferrous alloys, H. Jiang, X. Chen and L.	218 (2003) 215
Structural and electrochemical properties of opaque sol-gel deposited WO ₃ layers, G. Leftheriotis, S. Papaefthimiou, P. Yianoulis,		Hong	218 (2003) 305
A. Siokou and D. Kefalas	218 (2003) 275		
11. Slokou and D. Refulus	210 (2003) 273	Laser processing	
		Id ,d	
Ion bombardment		Femtosecond ultraviolet (248 nm) excimer laser processing of Teflon (PTFE), K.P.	
Deposition of indium tin oxide films on poly- carbonate substrates by direct metal ion beam deposition, D. Kim	218 (2003) 70	Adhi, R.L. Owings, T.A. Railkar, W.D. Brown and A.P. Malshe Tungsten microcone growth by laser irradia-	218 (2003) 17
AFM study of the effect of direct negative Ni ion beam energy on the evolution of Ni		tion, Y. Kawakami and E. Ozawa The effects of ambient He pressure on the	218 (2003) 175
nanoislands, D. Kim Gas cluster ion beam processing of gallium antimonide wafers for surface and sub-surface damage reduction, X. Li, W.D. Good-	218 (2003) 78	oxygen density of Er-doped SiO _x thin films grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310
hue, C. Santeufeimio, T.G. Tetreault, R. MacCrimmon, L.P. Allen, D. Bliss, K. Krishnaswami and C. Sung	218 (2003) 250		
		Luminescence	
Ion implantation		The effects of ambient He pressure on the oxygen density of Er-doped SiO_x thin films	
eous corrosion behavior of zircaloy-4, D.Q. Peng, X.D. Bai, X.W. Chen, Q.G. Zhou, X.Y. Liu and R.H. Yu	218 (2003) 7	grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310
Study of range distribution parameters for fluorine ions implantation in AgGaS ₂		Magnetic measurements	
crystal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang	218 (2003) 137		
C. Zhang	210 (2003) 137	Statistical approach for the antimal denosition	. 14 1
Ion scattering		of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F.	
Study on the surface of AlGaInP, J. Lian, Q. Wang, X. Cheng, A. Wei and Y. Wang	218 (2003) 12	Wang, F. Jin and ZY. Lee Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres,	218 (2003) 29
Adsorption geometry of ethyl iodide on clean	110 (2000)	W. Chen, X. Li, G. Xue, Z. Wang and	
and oxygen covered Ru(001) surfaces:		W. Zou	218 (2003) 215

Methanol		light detection, M. Ristova, Y. Kuo and H.H. Lee	218 (2003) 44
Interaction of methanol with Zr(0 0 0 1), N. Stojilovic, D.W. Weber and R.D. Ramsier	218 (2003) 188	Deposition of indium tin oxide films on poly- carbonate substrates by direct metal ion beam deposition, D. Kim	218 (2003) 70
Monte carlo simulations		Electronic properties of sulfur passivated undoped-n ⁺ type GaAs surface studied by photoreflectance, P. Jin, S.H. Pan, Y.G. Li,	
Study of range distribution parameters for fluorine ions implantation in AgGaS ₂ crys-	218 (2002) 127	C.Z. Zhang and Z.G. Wang On the electronic transport properties of polycrystalline ZnSe films, G.I. Rusu, M.E.	218 (2003) 210
tal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang Nanostructures	218 (2003) 137	Popa, G.G. Rusu and I. Salaoru Characterization of tungsten oxide films pro- duced by reactive pulsed laser deposition,	218 (2003) 222
AFM study of the effect of direct negative Ni		G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2003) 281
ion beam energy on the evolution of Ni nanoislands, D. Kim Annealing and morphology effects on the	218 (2003) 78	Oxidation	
Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, DH. Qin, JB. Ding and HL. Li Synthesis of carbon nanotubes/Si nanowires	106 (2003) 106	Electrochemical oxidation of the chalcopyrite	
core-sheath structure arrays and their field emission properties, M. Lu, M.K. Li, Z.J. Zhang and H.L. Li	218 (2003) 195	surface: an XPS and AFM study in solution at pH 4, M.L. Farquhar, P.L. Wincott, R.A. Wogelius and D.J. Vaughan	218 (2003) 34
Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres,	218 (2003) 215	Oxides	
W. Chen, X. Li, G. Xue, Z. Wang and W. Zou	218 (2003) 213	Study on the surface of AlGaInP, J. Lian,	
Nickel		Q. Wang, X. Cheng, A. Wei and Y. Wang	218 (2003) 12
AFM study of the effect of direct negative Ni ion beam energy on the evolution of Ni		Study of the surface roughness of CVD-tung- sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162
nanoislands, D. Kim XPS investigation of surface films on high Cr- Ni ferritic and austenitic stainless steels, G.	218 (2003) 78	Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres, W. Chen, X. Li, G. Xue, Z. Wang and W. Zou	218 (2003) 215
Lothongkum, S. Chaikittisilp and A.W. Lothongkum	218 (2003) 202	Structural and electrochemical properties of opaque sol-gel deposited WO ₃ layers, G.	210 (2000) 210
Nitrogen		Leftheriotis, S. Papaefthimiou, P. Yianoulis, A. Siokou and D. Kefalas Characterization of tungsten oxide films pro-	218 (2003) 275
Characterization of complex (B + C + N) diffusion layers formed on chromium and		duced by reactive pulsed laser deposition, G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2003) 281
nickel-based low-carbon steel, M. Kulka and A. Pertek	218 (2003) 113	Oxygen	
Nuclear reaction analysis		Adsorption geometry of ethyl iodide on clean and oxygen covered Ru(001) surfaces:	
Study of range distribution parameters for fluorine ions implantation in AgGaS ₂ crystal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang	218 (2003) 137	LEIS, XPS and TDS study, L. Óvári, J. Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329
Optical properties		Palladium	
Study of hydrogenated amorphous silicon thin films as a potential sensor for He–Ne laser		Polyaniline-palladium composite coatings for metallization of polyethylene substrate, J.G. Wang, K.G. Neoh and E.T. Kang	218 (2003) 231
•			

Phosphorus		Plasma processing	
Study on the surface of AlGaInP, J. Lian, Q. Wang, X. Cheng, A. Wei and Y. Wang	218 (2003) 12	Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and	219 (2002) 44
Photoelectron spectroscopy		H.H. Lee Surface chemistry of carbon removal from indium tin oxide by base and plasma treat-	218 (2003) 44
Effect of cerium ion implantation on the aqueous corrosion behavior of zircaloy-4, D.Q. Peng, X.D. Bai, X.W. Chen, Q.G. Zhou,		ment, with implications on hydroxyl termination, J.A. Chaney, S.E. Koh, C.S. Dulcey and P.E. Pehrsson	218 (2003) 258
X.Y. Liu and R.H. Yu	218 (2003) 7		The Internal
Femtosecond ultraviolet (248 nm) excimer laser processing of Teflon (PTFE), K.P. Adhi, R.L. Owings, T.A. Railkar, W.D.		Polymers	
Brown and A.P. Malshe Electrochemical oxidation of the chalcopyrite surface: an XPS and AFM study in solution	218 (2003) 17	Femtosecond ultraviolet (248 nm) excimer laser processing of Teflon (PTFE), K.P. Adhi, R.L. Owings, T.A. Railkar, W.D.	
at pH 4, M.L. Farquhar, P.L. Wincott, R.A. Wogelius and D.J. Vaughan Characterization of polyaniline-polypyrrole	218 (2003) 34	Brown and A.P. Malshe Increased hole injection in organic diodes by grafting of dipolar molecules on indium—tin	218 (2003) 17
composite coatings on low carbon steel: a XPS and infrared spectroscopy study, R. Rajagopalan and J.O. Iroh	218 (2003) 58	oxide, P. Sigaud, JN. Chazalviel, F. Oza- nam and K. Lahlil Characterization of polyaniline-polypyrrole	218 (2003) 54
Deposition of indium tin oxide films on poly- carbonate substrates by direct metal ion	210 (2000) 00	composite coatings on low carbon steel: a XPS and infrared spectroscopy study, R.	
beam deposition, D. Kim XPS investigation of surface films on high Cr-	218 (2003) 70	Rajagopalan and J.O. Iroh Deposition of indium tin oxide films on poly-	218 (2003) 58
Ni ferritic and austenitic stainless steels, G. Lothongkum, S. Chaikittisilp and A.W.		carbonate substrates by direct metal ion beam deposition, D. Kim	218 (2003) 70
Lothongkum Polyaniline-palladium composite coatings for metallization of polyethylene substrate,	218 (2003) 202	The electrochemical homopolymerization of furan and thiophene and the structural elucidation of their bipolymer films, M.	210 (2003) 10
J.G. Wang, K.G. Neoh and E.T. Kang Structural and electrochemical properties of opaque sol-gel deposited WO ₃ layers, G. Leftheriotis, S. Papaefthimiou, P. Yianoulis,	218 (2003) 231	Kabasakaloğlu, M. Talu, F. Yıldırım and B. Sarı Polyaniline-palladium composite coatings for metallization of polyethylene substrate,	218 (2003) 84
A. Siokou and D. Kefalas Characterization of tungsten oxide films pro-	218 (2003) 275	J.G. Wang, K.G. Neoh and E.T. Kang	218 (2003) 231
duced by reactive pulsed laser deposition, G. Soto, La Cruz W. De, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2003) 281	Pulsed laser deposition	
Adsorption geometry of ethyl iodide on clean and oxygen covered Ru(001) surfaces: LEIS, XPS and TDS study, L. Óvári, J. Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329	Characterization of tungsten oxide films produced by reactive pulsed laser deposition, G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H.	
Photovoltaic effects		Farías The effects of ambient He pressure on the oxygen density of Er-doped SiO _x thin films	218 (2003) 281
Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and		grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310
H.H. Lee Gas cluster ion beam processing of gallium antimonide wafers for surface and sub-sur-	218 (2003) 44	Ruthenium	
face damage reduction, X. Li, W.D. Goodhue, C. Santeufeimio, T.G. Tetreault, R. MacCrimmon, L.P. Allen, D. Bliss, K.		Adsorption geometry of ethyl iodide on clean and oxygen covered Ru(001) surfaces: LEIS, XPS and TDS study, L. Óvári, J.	
Krishnaswami and C. Sung	218 (2003) 250	Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329

Schottky barrier		Experiment and simulation of grain growth in a bidimensional polycrystalline film, Jm.	
Effect of series resistance on the performance of high resistivity silicon Schottky diode, A.		Zhang, Kw. Xu and V. Ji	218 (2003) 267
Keffous, M. Siad, S. Mamma, Y. Belkacem,		Steel	
C. Lakhdar Chaouch, H. Menari, A. Dahmani and W. Chergui	218 (2003) 336		
		Characterization of polyaniline-polypyrrole composite coatings on low carbon steel: a	
Selenium		XPS and infrared spectroscopy study, R. Rajagopalan and J.O. Iroh	218 (2003) 58
On the electronic transport properties of poly-		Characterization of complex (B + C + N)	218 (2003) 38
crystalline ZnSe films, G.I. Rusu, M.E. Popa, G.G. Rusu and I. Salaoru	218 (2003) 222	diffusion layers formed on chromium and nickel-based low-carbon steel, M. Kulka and A. Pertek	218 (2003) 113
Semorium		XPS investigation of surface films on high Cr- Ni ferritic and austenitic stainless steels, G.	230 (2000) 120
Statistical approach for the optimal deposition		Lothongkum, S. Chaikittisilp and A.W.	
of Cr underlayer for SmCo/Cr magnetic		Lothongkum	218 (2003) 202
films, XH. Xu, HS. Wu, JF. Duan, F. Wang, F. Jin and ZY. Lee	218 (2003) 29	Sulphur	
Silicon		Electronic properties of sulfur passivated undoped-n ⁺ type GaAs surface studied by	
Study of hydrogenated amorphous silicon thin		photoreflectance, P. Jin, S.H. Pan, Y.G. Li,	
films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and		C.Z. Zhang and Z.G. Wang	218 (2003) 210
H.H. Lee	218 (2003) 44	Sulphides	
Synthesis of carbon nanotubes/Si nanowires core-sheath structure arrays and their field		Sulphiaes	
emission properties, M. Lu, M.K. Li, Z.J. Zhang and H.L. Li	218 (2003) 195	Electrochemical oxidation of the chalcopyrite	
Effect of series resistance on the performance	210 (2003) 173	surface: an XPS and AFM study in solution at pH 4, M.L. Farquhar, P.L. Wincott, R.A.	
of high resistivity silicon Schottky diode, A. Keffous, M. Siad, S. Mamma, Y. Belkacem,		Wogelius and D.J. Vaughan Study of range distribution parameters for	218 (2003) 34
C. Lakhdar Chaouch, H. Menari, A. Dah-	219 (2002) 226	fluorine ions implantation in AgGaS2 crys-	
mani and W. Chergui	218 (2003) 336	tal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang	218 (2003) 137
Silicon oxide			
The effects of ambient He pressure on the		Surface roughness	
oxygen density of Er-doped SiO _x thin films		Study of the surface roughness of CVD-tung-	
grown by laser ablation of a Si:Er ₂ O ₃ target, S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang,		sten oxide thin films, R.E. Tanner, A. Sze-	
K.H. Yoo and J.S. Ha	218 (2003) 310	keres, D. Gogova and K. Gesheva	218 (2003) 162
Silver		Thermal desorption	
Study of range distribution parameters for		Determination of kinetic parameters from tem-	
fluorine ions implantation in AgGaS ₂ crystal, X. Liu, F. Li, Q. Lu, Y. Xia and C. Zhang	218 (2003) 137	perature programmed desorption curves,	
		M. Bhattacharya, W.G. Devi and P.S. Mazumdar	218 (2003) 1
Sputter deposition		Interaction of methanol with Zr(0 0 0 1), N. Stojilovic, D.W. Weber and R.D. Ramsier	218 (2003) 188
Statistical approach for the optimal deposition		Adsorption geometry of ethyl iodide on clean	2200) 100
of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F.		and oxygen covered Ru(001) surfaces: LEIS, XPS and TDS study, L. Óvári, J.	
Wang, F. Jin and ZY. Lee	218 (2003) 29	Kiss, A.P. Farkas and F. Solymosi	218 (2003) 329

Thin films		G. Soto, W. De La Cruz, J.A. Díaz, R. Machorro, F.F. Castillón and M.H. Farías	218 (2003) 281
Statistical approach for the optimal deposition of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F.		Work function	
Wang, F. Jin and ZY. Lee Study of hydrogenated amorphous silicon thin films as a potential sensor for He-Ne laser light detection, M. Ristova, Y. Kuo and	218 (2003) 29	Electrochemical characterization of copper surface modified by <i>n</i> -alkanethiols in chloride-containing solutions, H.Y. Ma, C. Yang, B.S. Yin, G.Y. Li, S.H. Chen	
H.H. Lee Study of the surface roughness of CVD-tung-	218 (2003) 44	and J.L. Luo	218 (2003) 143
sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva On the electronic transport properties of poly-	218 (2003) 162	X-ray diffraction	
crystalline ZnSe films, G.I. Rusu, M.E. Popa, G.G. Rusu and I. Salaoru Experiment and simulation of grain growth in a	218 (2003) 222	Statistical approach for the optimal deposition of Cr underlayer for SmCo/Cr magnetic films, XH. Xu, HS. Wu, JF. Duan, F.	
bidimensional polycrystalline film, Jm. Zhang, Kw. Xu and V. Ji	218 (2003) 267	Wang, F. Jin and ZY. Lee Annealing and morphology effects on the	218 (2003) 29
Structural and electrochemical properties of opaque sol-gel deposited WO ₃ layers, G. Leftheriotis, S. Papaefthimiou, P. Yianoulis, A. Siokou and D. Kefalas Characterization of tungsten oxide films pro-	218 (2003) 275	Fe _{0.39} Co _{0.61} nanowire arrays, Y. Guo, DH. Qin, JB. Ding and HL. Li Magnetic and conducting particles: preparation of polypyrrole layer on Fe ₃ O ₄ nanospheres,	106 (2003) 106
duced by reactive pulsed laser deposition, G. Soto, W. De La Cruz, J.A. Díaz,		W. Chen, X. Li, G. Xue, Z. Wang and W. Zou On the electronic transport properties of poly-	218 (2003) 215
R. Machorro, F.F. Castillón and M.H. Farías The effects of ambient He pressure on the	218 (2003) 281	crystalline ZnSe films, G.I. Rusu, M.E. Popa, G.G. Rusu and I. Salaoru	218 (2003) 222
oxygen density of Er-doped SiO_x thin films grown by laser ablation of a $Si:Er_2O_3$ target,		Yttrium	
S.M. Park, C.H. Bae, S.H. Nam, Y.R. Jang, K.H. Yoo and J.S. Ha	218 (2003) 310	Theoretical analysis of strain energy-driven abnormal grain growth in metallic films with hcp ((c/a) < 1.633) structure on rigid	
Titanium		substrates, JM. Zhang and KW. Xu	218 (2003) 245
Theoretical analysis of strain energy-driven abnormal grain growth in metallic films with hcp $((c/a) < 1.633)$ structure		Zinc	
on rigid substrates, JM. Zhang and KW. Xu	218 (2003) 245	On the electronic transport properties of polycrystalline ZnSe films, G.I. Rusu, M.E. Popa, G.G. Rusu and I. Salaoru	218 (2003) 222
Tungsten		Zirconium	
Study of the surface roughness of CVD-tung-			
sten oxide thin films, R.E. Tanner, A. Sze- keres, D. Gogova and K. Gesheva	218 (2003) 162	Effect of cerium ion implantation on the aqueous corrosion behavior of zircaloy-4, D.Q.	
Tungsten microcone growth by laser irradia- tion, Y. Kawakami and E. Ozawa Structural and electrochemical properties of	218 (2003) 175	Peng, X.D. Bai, X.W. Chen, Q.G. Zhou, X.Y. Liu and R.H. Yu Interaction of methanol with Zr(0 0 0 1), N.	218 (2003) 7
opaque sol-gel deposited WO ₃ layers, G. Leftheriotis, S. Papaefthimiou, P. Yianoulis,	219 (2002) 275	Stojilovic, D.W. Weber and R.D. Ramsier Theoretical analysis of strain energy-driven	218 (2003) 188
 A. Siokou and D. Kefalas Characterization of tungsten oxide films produced by reactive pulsed laser deposition, 	218 (2003) 275	abnormal grain growth in metallic films with hcp ((c/a) < 1.633) structure on rigid substrates, JM. Zhang and KW. Xu	218 (2003) 245